PH2925U

N-channel TrenchMOS ultra low level FET

Rev. 04 — 24 February 2009

Product data sheet

1. Product profile

1.1 General description

Ultra low level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Interfaces directly with low voltage gate drivers
- Low conduction losses due to low on-state resistance

1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Portable equipment
- Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	25	V
I _D	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 4.5 \text{V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 10</u> ; see <u>Figure 11</u>	-	20.2	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 8; see Figure 9	-	2.3	3	mΩ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		G
4	G	gate	9	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH2925U	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

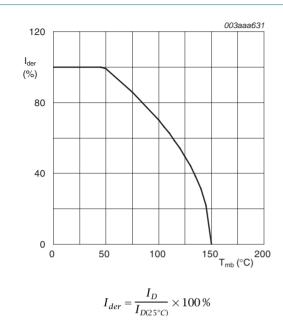
Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	25	V
V_{DGR}	drain-gate voltage	$T_j \le 150$ °C; $T_j \ge 25$ °C; $R_{GS} = 20$ kΩ	-	25	V
V_{GS}	gate-source voltage		-10	10	V
I_D	drain current	$V_{GS} = 4.5 \text{ V}; T_{mb} = 100 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	70	Α
		V _{GS} = 4.5 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	100	Α
I _{DM}	peak drain current	$t_p \le 10 \mu\text{s}; \text{ pulsed}; T_{mb} = 25 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure 3}}{}$	-	300	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}\text{C}$	-	52	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	150	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 70.7 A; V_{sup} ≤ 25 V; unclamped; t_p = 0.22 ms; R_{GS} = 50 Ω	-	250	mJ

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Normalized continuous drain current as a function of mounting base temperature

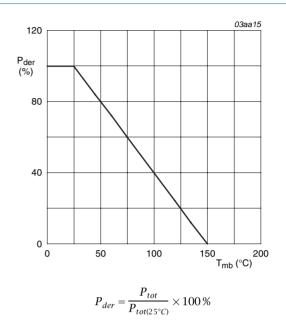


Fig 2. Normalized total power dissipation as a function of mounting base temperature

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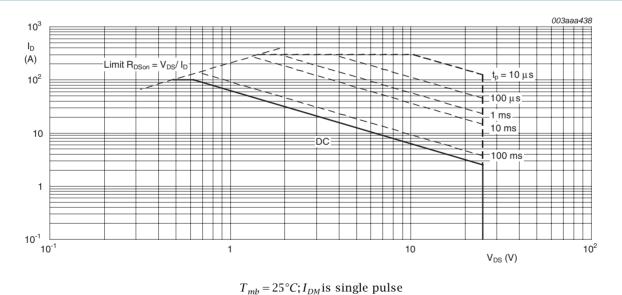


Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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Thermal characteristics

Thermal characteristics Table 5.

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W

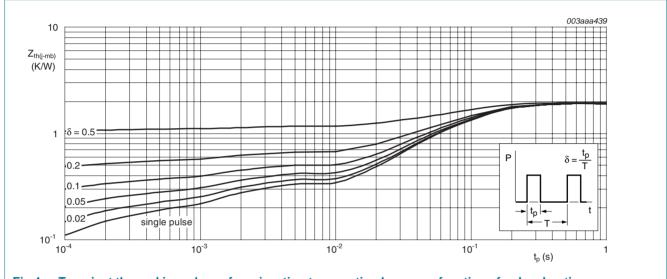


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

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Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	racteristics			- 7 F		3
V _{(BR)DSS}	drain-source	I _D = 250 μA; V _{GS} = 0 V; T _i = -55 °C	22.5	_	-	V
(BK)D33	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_i = 25 °C$	25	_	-	V
V _{GS(th)} gate-source threshold voltage		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see Figure 6; see Figure 7	-	-	1.2	V
	J	$I_D = 1 \text{ mA; } V_{DS} = V_{GS}; T_j = 150 \text{ °C;}$ see Figure 6; see Figure 7	0.25	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 7; see Figure 6	0.45	0.7	0.95	V
I _{DSS}	drain leakage current	V _{DS} = 25 V; V _{GS} = 0 V; T _i = 150 °C	-	-	500	μΑ
		V _{DS} = 25 V; V _{GS} = 0 V; T _i = 25 °C	-	0.06	1	μΑ
I _{GSS}	gate leakage current	V _{GS} = 10 V; V _{DS} = 0 V; T _j = 25 °C	-	20	100	nA
		V _{GS} = -10 V; V _{DS} = 0 V; T _j = 25 °C	-	20	100	nA
Doon	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 150 \text{ °C}$; see Figure 8; see Figure 9	-	3.6	4.8	mΩ
		$V_{GS} = 2.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}$	-	3.2	4.2	mΩ
		$V_{GS} = 4.5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 8; see Figure 9	-	2.3	3	mΩ
R_G	internal gate resistance (AC)	f = 1 MHz; T _j = 25 °C	-	1.55	-	Ω
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}$; $V_{DS} = 10 \text{ V}$; $V_{GS} = 4.5 \text{ V}$;	-	92	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	12	-	nC
Q_{GD}	gate-drain charge		-	20.2	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	I_D = 50 A; V_{DS} = 10 V; T_j = 25 °C; see Figure 10; see Figure 11	-	1.6	-	V
C _{iss}	input capacitance	V _{DS} = 10 V; V _{GS} = 0 V; f = 1 MHz;	-	6150	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	1170	-	pF
C _{rss}	reverse transfer capacitance		-	814	-	pF
d(on)	turn-on delay time	$V_{DS} = 10 \text{ V}; R_L = 1 \Omega; V_{GS} = 4.5 \text{ V};$	-	30	-	ns
r	rise time	$R_{G(ext)} = 4.7 \Omega; T_j = 25 °C$	-	80	-	ns
d(off)	turn-off delay time		-	258	-	ns
t _f	fall time		-	114	-	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 13	-	0.72	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; \text{ d}I_S/\text{d}t = -100 \text{ A/}\mu\text{s}; \text{ V}_{GS} = 0 \text{ V};$ $V_{DS} = 25 \text{ V}$	-	60	-	ns

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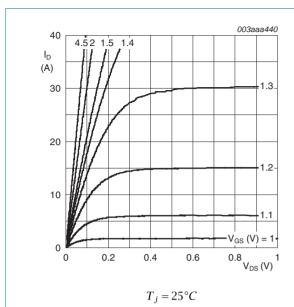


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

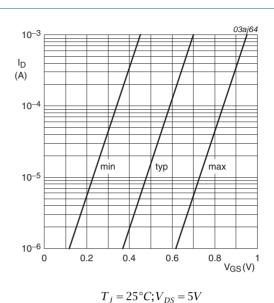


Fig 6. Sub-threshold drain current as a function of

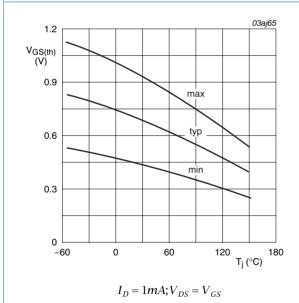


Fig 7. Gate-source threshold voltage as a function of junction temperature

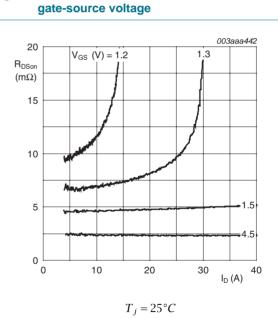


Fig 8. Drain-source on-state resistance as a function of drain current; typical values

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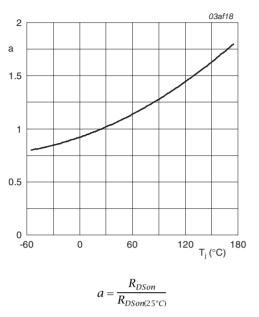
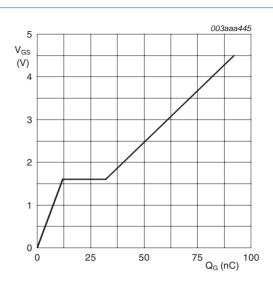


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature



$$I_D = 50A; V_{DS} = 10V$$

Fig 10. Gate-source voltage as a function of gate charge; typical values

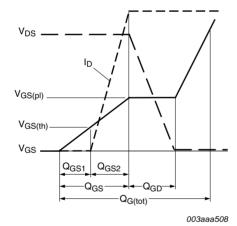
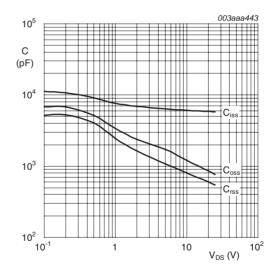


Fig 11. Gate charge waveform definitions



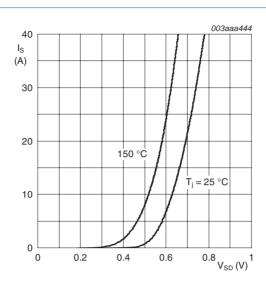
$$V_{GS} = 0V; f = 1MHz$$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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 $T_j = 25 \,^{\circ} C \text{ and } 150 \,^{\circ} C; V_{GS} = 0V$

Fig 13. Source current as a function of source-drain voltage; typical values

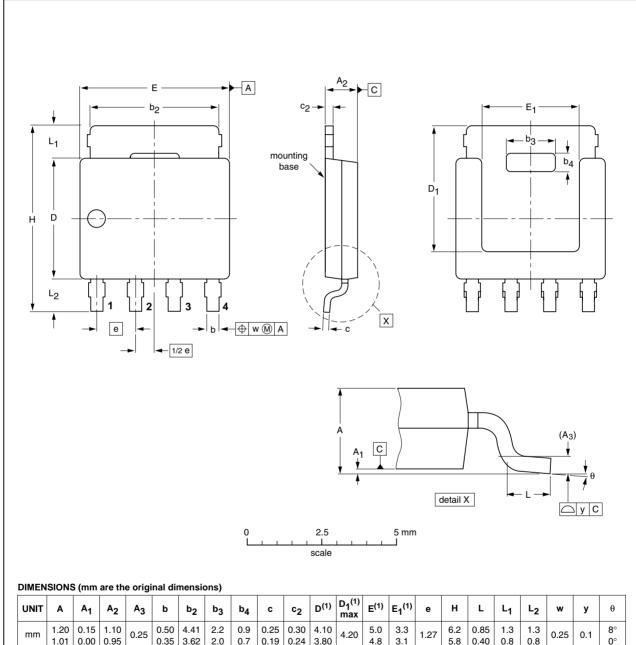
Product data sheet

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669

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UNIT	A	A ₁	A ₂	А3	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	0.30 0.24	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

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Fig 14. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

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Document ID	Release date	Data sheet status	Change notice	Supersedes
PH2925U_4	20090224	Product data sheet	-	PH2925U_3
Modifications:	guidelines	of this data sheet has be of NXP Semiconductors.		
	 Legal texts 	have been adapted to the	e new company name v	vhere appropriate.
PH2925U_3	20051129	Product data sheet	-	PH2925U-02
PH2925U-02 (9397 750 13064)	20040408	Product data	-	PH2925U-01
PH2925U-01 (9397 750 11407)	20030502	Product data	-	-

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Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- The term 'short data sheet' is explained in section "Definitions"
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